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Bib Data Sheet FILING DATE **ATTORNEY GROUP ART UNIT** CLASS SERIAL NUMBER DOCKET NO. 02/27/2002 250 2881 10/083,481 29273/559 RULE **APPLICANTS** Yuko Iwabuchi, Mito-shi, JAPAN; Hideo Todokoro, Nishitama-gun, JAPAN; Hiroyoshi Mori, Hitachinaka-shi, JAPAN; Mitsugu Sato, Hitachinaka-shi, JAPAN; Yasutsugu Usami, Toshina-ku, JAPAN; Mikio Ichihashi, Kodaira-shi, JAPAN; Satoru Fukuhara, Hitachinaka-shi, JAPAN; Hiroyuki Shinada, Chofu-shi, JAPAN; Yutaka Kaneko, Hachiouji-shi, JAPAN; Katsuya Sugiyama, Kashiwa-shi, JAPAN; Atsuko Takafuji, Nerima-ku, JAPAN; Hiroshi Toyama, Hachiouji-shi, JAPAN; '* CONTINUING DATA * THIS APPLICATION IS A CON OF 09/883,184 06/19/2001 WHICH IS A CON OF 09/131,383 08/07/1998 PAT 6,348,690 ** FOREIGN APPLICATIONS ** JAPAN 9-212908 08/07/1997 IF REQUIRED, FOREIGN FILING LICENSE GRANTED 04/11/2002 ☑ xes □ no Foreign Priority claimed INDEPENDENT SHEETS TOTAL STATE OR yes no Met after CLAIMS 35 USC 119 (a-d) conditions **DRAWING** CLAIMS COUNTRY met Allowance Borman 9/1 16 **JAPAN** 10 Verified and Initials Examiner's Signature Acknowledged ADDRESS 23838 TITLE Method and an apparatus of an inspection system using an electron beam All Fees 1.16 Fees (Filing) JFEES: Authority has been given in Paper ☐ 1.17 Fees (Processing Ext. of FILING FEE to charge/credit DEPOSIT ACCOUNT time) **RECEIVED** for following: 740 No. ___ 1.18 Fees (Issue) Other BEST AVAILABLE COPY